

3.23: Resolution

In crystal structure determination, the term **resolution** is used to describe the ability to distinguish between neighboring features in an electron density map. By convention, it is defined as the minimum plane spacing given by [Bragg's law](#) for a particular set of X-ray diffraction intensities. The resolution improves with an increase in the maximum value of $(\sin \theta) / \lambda$ at which reflections are measured.

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